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Test Method for Phosphor Linearity

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CONTENTS

		Page
Foreword		ii
Clause		
1	Introduction	1
1.1	Charge per unit area per pulse	1
2	Definitions	2
3	Typical CRT test conditions for measuring phosphor linearity	2
Tables		
1	Per unit area excitation densities, charge ϵ vs energy Q	1
2	Luminance and chromaticity data vs scan size and excitation density	3
Figures		
1	Phosphor linearity vs excitation density	4